

# N-Channel 80 V (D-S) MOSFET

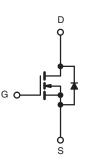
PRODUCT SUMMARY					
$V_{DS}$ (V) $R_{DS(on)}$ ( $\Omega$ ) MAX.		I <sub>D</sub> (A)	Q <sub>g</sub> (TYP.)		
80	0.0065 at V <sub>GS</sub> = 10 V	120	53.5 nC		
	0.0010 at V <sub>GS</sub> = 7.5 V	110	33.3110		

## **FEATURES**

- ThunderFET® power MOSFET
- Maximum 175 °C junction temperature
- $\bullet$  100 %  $R_g$  and UIS tested
- Material categorization: for definitions of compliance please see







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> = 25 °C, unless otherwise noted)					
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V <sub>DS</sub>	80	V		
Gate-Source Voltage	$V_{GS}$	± 20			
Continuous Drain Current (T,I = 150 °C)	T <sub>C</sub> = 25 °C		120		
Continuous Drain Current (1) = 150 C)	T <sub>C</sub> = 125 °C	l <sub>D</sub>	65		
Pulsed Drain Current (t = 100 μs)	I <sub>DM</sub>	225	А		
Avalanche Current L = 0.1 mH		I <sub>AS</sub>		50	
Single Avalanche Energy <sup>a</sup>	L = 0.1 IIII	E <sub>AS</sub>	125	mJ	
Maximum Power Dissipation <sup>a</sup>	T <sub>C</sub> = 25 °C	В	370 b	W	
iviaximum Fower Dissipation 4	T <sub>C</sub> = 125 °C	$ P_D$	120 <sup>b</sup>	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	
Operating Junction and Storage Temperature F	T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C		

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	LIMIT	UNIT		
Junction-to-Ambient (PCB Mount) <sup>c</sup>	R <sub>thJA</sub>	40	°C/W		
Junction-to-Case (Drain)	R <sub>thJC</sub>	0.75	C/VV		

#### Notes

- a. Duty cycle  $\leq$  1 %.
- b. See SOA curve for voltage derating.
- c. When mounted on 1" square PCB (FR4 material).

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PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80	-	=	V	
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	2.5	-	4.5	V	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
		$V_{DS} = 80 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS}$ = 80 V, V $_{GS}$ = 0 V, $T_{J}$ = 125 $^{\circ}C$	-	-	100	μA	
		$V_{DS} = 80 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 175 ^{\circ}\text{C}$	-	-	2	mA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	90	-	-	Α	
Drain Sauras On State Besistense 2	В	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A	-	0.0065	-	0	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 7.5 \text{ V}, I_D = 30 \text{ A}$	-	0.0100	-	Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A	-	85	-	S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>		-	3330	-	pF	
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 40 V, f = 1 MHz	-	1395	=		
Reverse Transfer Capacitance	C <sub>rss</sub>		-	95	-		
Total Gate Charge <sup>c</sup>	Qg		-	53.5	81		
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$	-	14.5	=	nC	
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>		-	13.2	-		
Gate Resistance	$R_g$	f = 1 MHz	0.9	1.9	3.8	Ω	
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>		-	13	26		
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD}$ = 40 V, $R_L$ = 1.67 $\Omega$	-	22	44	20	
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	$I_D \cong 30 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	-	27	54	ns	
Fall Time <sup>c</sup>	t <sub>f</sub>		-	9	18		
Drain-Source Body Diode Ratings at	nd Characteris	stics <sup>b</sup> (T <sub>C</sub> = 25 °C)					
Pulsed Current (t = 100 μs)	I <sub>SM</sub>		-	-	240	Α	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = 30 A, V <sub>GS</sub> = 0 V	-	0.86	1.4	٧	
Reverse Recovery Time	t <sub>rr</sub>		-	88	176	ns	
Peak Reverse Recovery Charge	I <sub>RM(REC)</sub>	$I_F = 30 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$	-	5	10	Α	
Reverse Recovery Charge	Recovery Charge Q <sub>rr</sub>		-	0.22	0.44	μC	

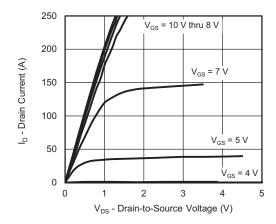
#### Notes

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

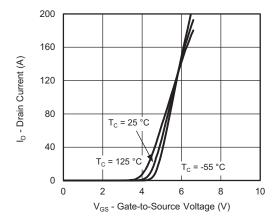
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



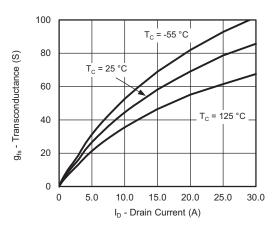
# **TYPICAL CHARACTERISTICS** ( $T_A = 25$ °C, unless otherwise noted)



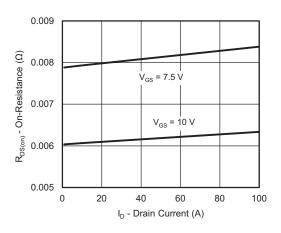
#### **Output Characteristics**



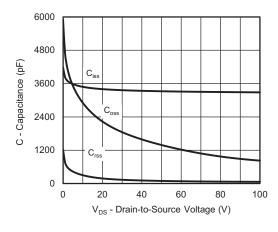
**Transfer Characteristics** 



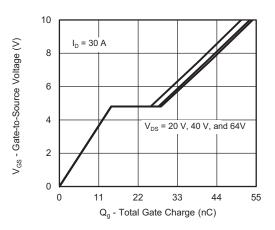
Transconductance



On-Resistance vs. Drain Current



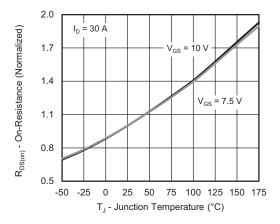
Capacitance



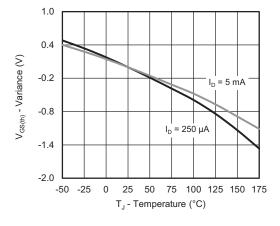
**Gate Charge** 



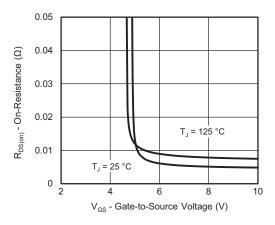
## **TYPICAL CHARACTERISTICS** (T<sub>A</sub> = 25 °C, unless otherwise noted)



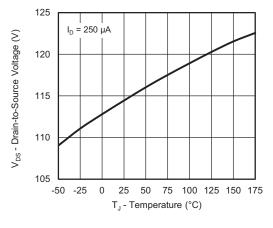
On-Resistance vs. Junction Temperature



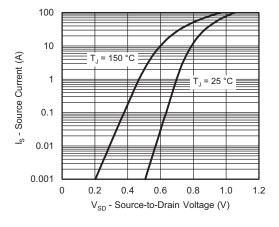
Threshold Voltage



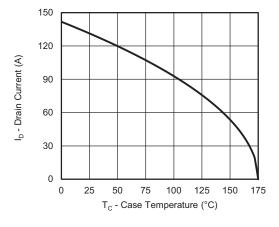
On-Resistance vs. Gate-to-Source Voltage



**Drain Source Breakdown vs. Junction Temperature** 



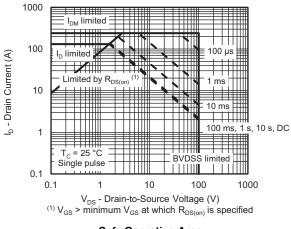
**Source Drain Diode Forward Voltage** 

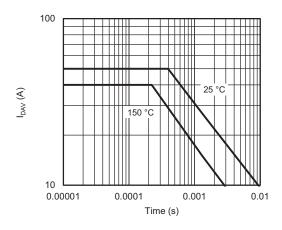


**Current De-Rating** 



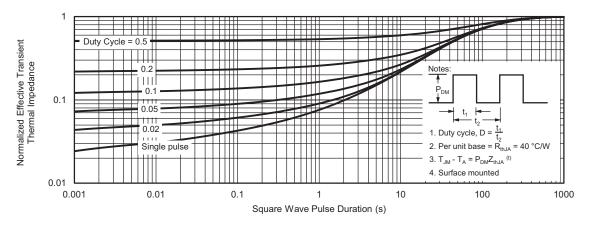
# **THERMAL RATINGS** ( $T_A = 25$ °C, unless otherwise noted)





Safe Operating Area

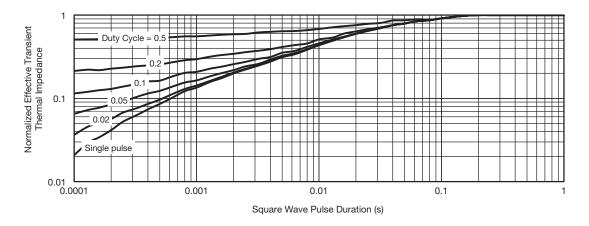
I<sub>DAV</sub> vs. Time



Normalized Thermal Transient Impedance, Junction-to-Ambient



## **THERMAL RATINGS** (T<sub>A</sub> = 25 °C, unless otherwise noted)



#### Normalized Thermal Transient Impedance, Junction-to-Case

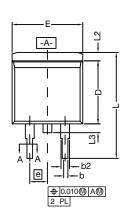
#### Note

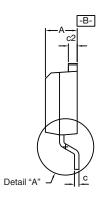
- The characteristics shown in the two graphs
  - Normalized Transient Thermal Impedance Junction to Ambient (25 °C)
  - Normalized Transient Thermal Impedance Junction to Case (25 °C)

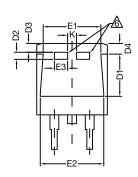
are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.



# TO-263 (D<sup>2</sup>PAK): 3-LEAD

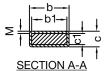








DETAIL A (ROTATED 90°)



≥ ±	b	ļ
27	<u> </u>	_
ç	† SECTION A-A	t

- 1. Plane B includes maximum features of heat sink tab and plastic.
- 2. No more than 25 % of L1 can fall above seating plane by max. 8 mils.
- 3. Pin-to-pin coplanarity max. 4 mils.
- 4. \*: Thin lead is for SUB, SYB. Thick lead is for SUM, SYM, SQM.
- 5. Use inches as the primary measurement.

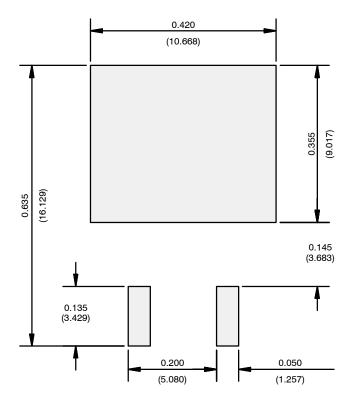
6 This feature is for thick lead.

		INC	HES	MILLIMETERS		
DIM.		MIN.	MAX.	MIN.	MAX.	
Α		0.160	0.190	4.064	4.826	
	b	0.020	0.039	0.508	0.990	
	b1	0.020	0.035	0.508	0.889	
	b2	0.045	0.055	1.143	1.397	
c*	Thin lead	0.013	0.018	0.330	0.457	
C	Thick lead	0.023	0.028	0.584	0.711	
c1	Thin lead	0.013	0.017	0.330	0.431	
CI	Thick lead	0.023	0.027	0.584	0.685	
	c2	0.045	0.055	1.143	1.397	
	D	0.340	0.380	8.636	9.652	
	D1	0.220	0.240	5.588	6.096	
	D2	0.038	0.042	0.965	1.067	
	D3	0.045	0.055	1.143	1.397	
	D4	0.044	0.052	1.118	1.321	
	Е	0.380	0.410	9.652	10.414	
	E1	0.245	-	6.223	-	
	E2	0.355	0.375	9.017	9.525	
	E3	0.072	0.078	1.829	1.981	
е		0.100 BSC		2.54 BSC		
K		0.045	0.055	1.143	1.397	
	L	0.575	0.625	14.605	15.875	
L1		0.090	0.110	2.286	2.794	
L2		0.040	0.055	1.016	1.397	
L3		0.050	0.070	1.270	1.778	
L4		0.010 BSC		0.254 BSC		
	М		0.002	-	0.050	
ECN: T13-0707-Rev. K, 30-Sep-13						

DWG: 5843



## RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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